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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Patent of: **Yasuo YAMAGISHI**

U.S. Patent No. **7,102,367**
Issued: **September 5, 2006**

Group Art Unit: **2829**

Examiner: **Jermele M. HOLLINGTON**

Serial No.: **10/621,445**

Filed: **July 18, 2003**

For. **PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,
CAPACITOR AND MANUFACTURING METHOD**

PETITION TO CORRECT INVENTORSHIP IN PATENT
UNDER 37 CFR § 1.324

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
Sir:

Date: January 25, 2007

Applicant respectfully request that the following names be deleted as inventors of the above-referenced patent: Takashi SHIOGA, John David BENIECKI and Kazuaki KURIHARA.

The invention of the above named three (3) individuals is no longer being claimed due to the cancellation of claims in the application.

Attached herewith are the following: Consent of Assignee to Change of Inventorship, Statements of each currently-named inventor agreeing to the change of inventorship; and a check in the amount of \$130.00 for the petition fee.

In the event any additional fees are required in connection with this paper, please charge Deposit Account No. 01-2340.

Respectfully submitted,

ARMSTRONG, KRATZ, QUINTOS, HANSON & BROOKS, LLP


William L. Brooks

Attorney for Applicant 01/26/2007 HMARZI1 00000077 10621445

Reg. No. 34,129

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Atty. Docket No. **030868**
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PATENT TRADEMARK OFFICE

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CAPACITOR AND MANUFACTURING METHOD**

CONSENT OF ASSIGNEE TO CHANGE OF INVENTORSHIP

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

I, Michio Nakamura (name), General Manager, Patent div. (title) of FUJITSU LIMITED, 1-1, Kamikodanaka 4-chome, Nakahara-ku, Kawasaki-shi Kanagawa 211-8588, Japan, the sole Assignee of the above-referenced patent application, hereby agree and consent to the deletion of Takashi SHIOGA, John David BENIECKI and Kazuaki KURIHARA as inventors of U.S. Patent 7,102,367.

Michio Nakamura
(Name) Michio Nakamura
(Title) General Manager, Patent div.
FUJITSU LIMITED
1-1, Kamikodanaka 4-chome
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January 10, 2007

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In re the Patent of: **Yasuo YAMAGISHI et al.**

U.S. Patent No. 7,102,367
Issued: **September 5, 2006**

Group Art Unit: **2829**

Examiner: **Jermele M. HOLLINGTON**

Serial No.: **10/621,445**

Confirmation No. **1112**

Filed: **July 18, 2003**

For. **PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,
CAPACITOR AND MANUFACTURING METHOD THEREFOR**

STATEMENT OF INVENTOR

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

I, Yasuo YAMAGISHI, hereby confirm that I am the sole inventor of the above-referenced patent, and I hereby agree and consent to the deletion of Takashi SHIOGA, John David BANIECKI and Kazuaki KURIHARA as inventors of U.S. Patent 7,102,367.

Yasuo Yamagishi
Yasuo YAMAGISHI

Jan. 09, 2007
Date

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Atty. Docket No. **030868**
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Patent of: **Yasuo YAMAGISHI et al.**

U.S. Patent No. 7,102,367
Issued: **September 5, 2006**

Group Art Unit: **2829**

Examiner: **Jermele M. HOLLINGTON**

Serial No.: **10/621,445**

Confirmation No. 1112

Filed: **July 18, 2003**

For. **PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,
CAPACITOR AND MANUFACTURING METHOD THEREFOR**

STATEMENT OF INVENTOR

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

I, Takeshi SHIOGA, hereby confirm that I am not an inventor of the above-referenced patent, and I hereby agree and consent to the deletion of Takashi SHIOGA, John David BANIECKI and Kazuaki KURIHARA as inventors of U.S. Patent 7,102,367.

Takeshi Shioiga
Takeshi SHIOGA

Dec. 28, 2006
Date

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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STATEMENT OF INVENTOR

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

I, John David BANIECKI, hereby confirm that I am not an inventor of the above-referenced patent application, and I hereby agree and consent to the deletion of Takashi SHIOGA, John David BANIECKI and Kazuaki KURIHARA as inventors of U.S. Patent 7,102,367.


John David BANIECKI

Jan 4, 2007
Date

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CAPACITOR AND MANUFACTURING METHOD THEREFOR**

STATEMENT OF INVENTOR

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

I, Kazuaki KURIHARA, hereby confirm that I am not an inventor of the above-referenced patent application, and I hereby agree and consent to the deletion of Takashi SHIOGA, John David BANIECKI and Kazuaki KURIHARA as inventors of U.S. Patent 7,102,367.


Kazuaki KURIHARA

Dec. 28, 2006
Date

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